

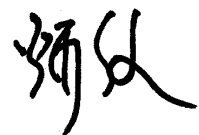


# Approval Sheet

Products	Dielectric Chip Antenna		
Customer	UMID		
Model	Metallifer		
Customer CODE			
Supplier	PARTRON		
Supplier CODE	ACS2450ICAMEB		
CLIPCOM	By designed	By checked	By approved
PARTRON	By designed	By checked	By approved
			
	Research 5 Team	Quality Assurance	Laboratory
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	02 / 09	02 / 09	02 / 09

**2009. 02. 09**



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MSL Level 1

ROHS-Y

# SPECIFICATION

MODEL : ACS2450ICAMEB

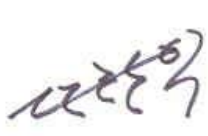

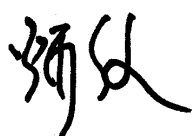
3D Structure



Top View



Bottom View

By designed	By checked	By approved
		
Research 5 Team	Quality Assurance	Laboratory
Chanik.Jeon	Nam-Sik.Min	Byoung-Jun.Yim
02 / 09	02 / 09	02 / 09

2009. 02. 09



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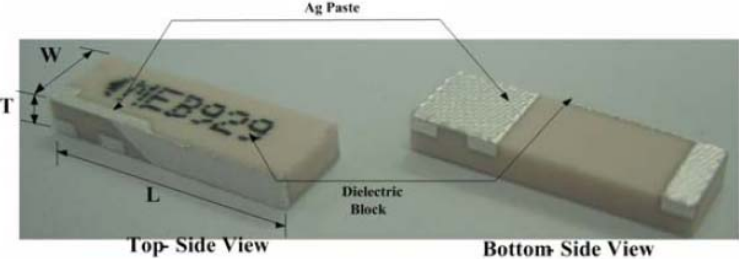


[illegible]



## 2. Summary of Parts

- This product is the internal dielectric chip antenna of radio communication, forms the pattern with Ag paste on the brick of dielectric block and materializes the characteristics

Type	Only Bulk Ceramic	
Material	Dielectric Block	Mg <sub>2</sub> SiO <sub>4</sub> (Magnesium Silicate)
	Electrode Paste	Ag
Size[mm]	W = 3.0±0.1	
	L = 9.0±0.1	
	T = 1.2±0.1	
Flatness Level	0.04	
MSL Level	MSL Level 1	
ESD Level	More than 15 kV (HBM CLASS 3B)	
Version	Revision 1.0	

## 3. Critical to Quality (CTQ)

- The following list is specified as the emphasis management list and managed.

CTQ ITEM	Specification Reason
Shape weight, size	Shape weight and size determines the electric block size after plastic and the dielectric block size effects the level of detail for the printing.
Plastic Size	The size after plastic effects the level of detail for the printing.
Printing Size	The level of detail for printing size is an essential list of the BT antenna.

CTF ITEM	Specification Reason
Single Element measurement SWR	An important Parameter classifying the electrical characteristics.

- require attention for the following list.

ITEM	Content
Keeping	Sealing tightly when keeping for a long time.
Action	Maybe characteristics changes when changing any design.



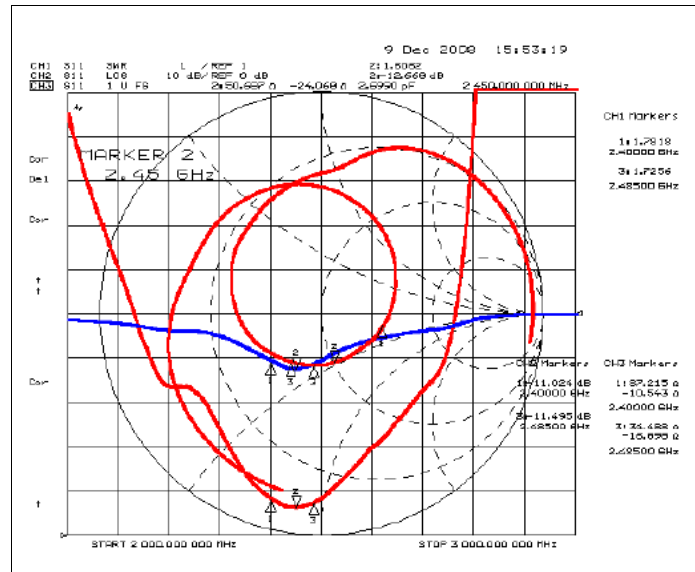
## 4. Electrical Characteristics

### 4.1 Set Condition

ITEM				SPEC
Frequency Range [MHz]				2400 ~ 2485
SWR [Max]				3.0 : 1 [ Typ 2.0:1 ]
Input Impedance [ $\Omega$ ]				50 Ohm
Polarization				Linear
Gain[dBi]	Total Gain ( Peak / Avg ) [dBi]			-0.9 / -6.6
	Azimuth	Theta	Peak	-1.38
			Average	-5.77
		Phi	Peak	-1.13
			Average	-6.58
	Elevation 1	Theta	Peak	-2.99
			Average	-7.74
		Phi	Peak	-2.17
			Average	-6.94
	Elevation 2	Theta	Peak	-2.45
			Average	-7.78
		Phi	Peak	-0.83
			Average	-5.23



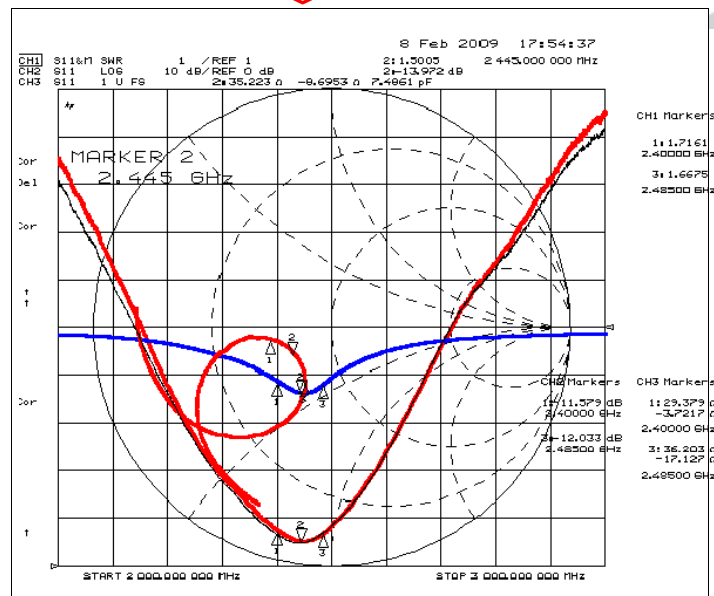
#### 4.2 S11 Graph of Set Condition



#### 4.3 Test Fixture Condition

ITEM	SPEC
Frequency Range [MHz]	2400 ~ 2485
Lower frequency(2400MHz) SWR [Min~Max]	3.0 : 1(Typ 2.0 :1)
Upper frequency(2485MHz) SWR [Min~Max]	3.0 : 1(Typ 2.0 :1)

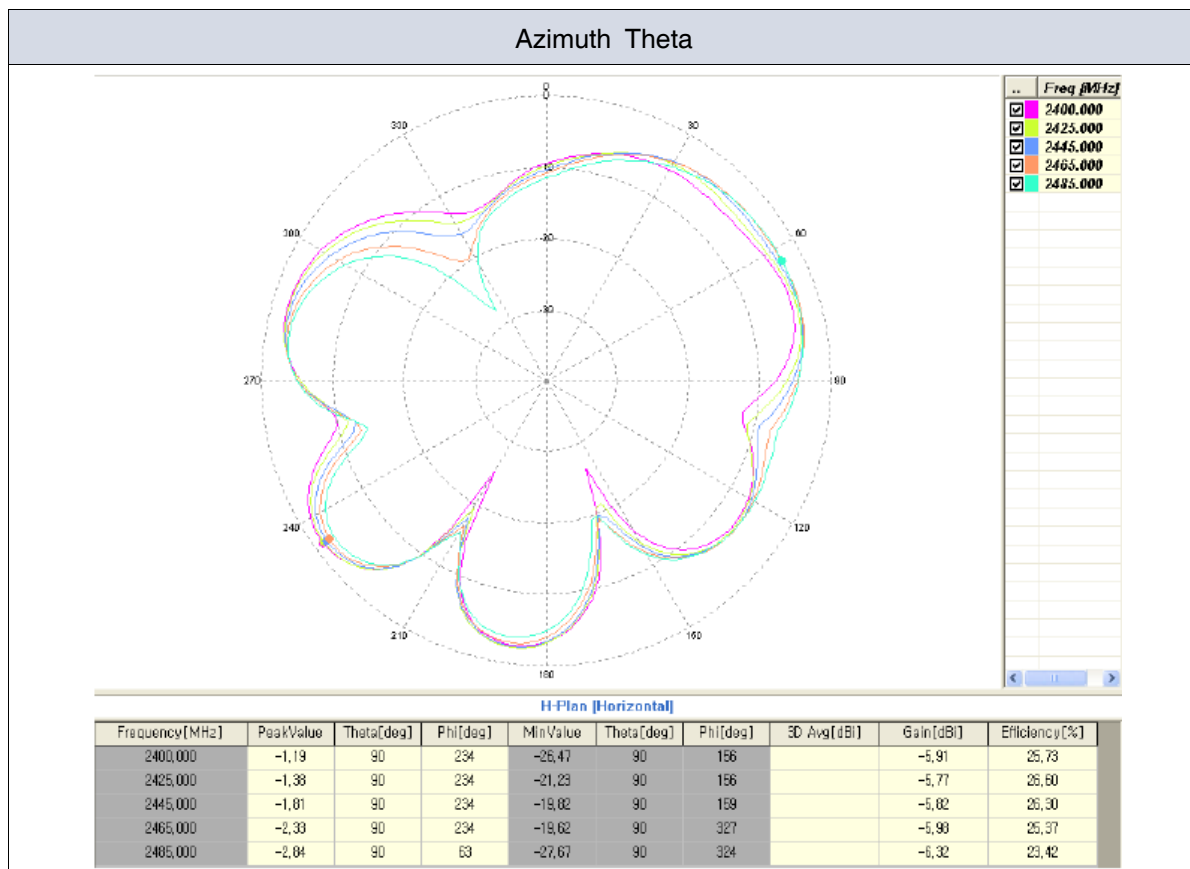
#### 4.4 S11 Graph of Test Fixture Condition CTQ





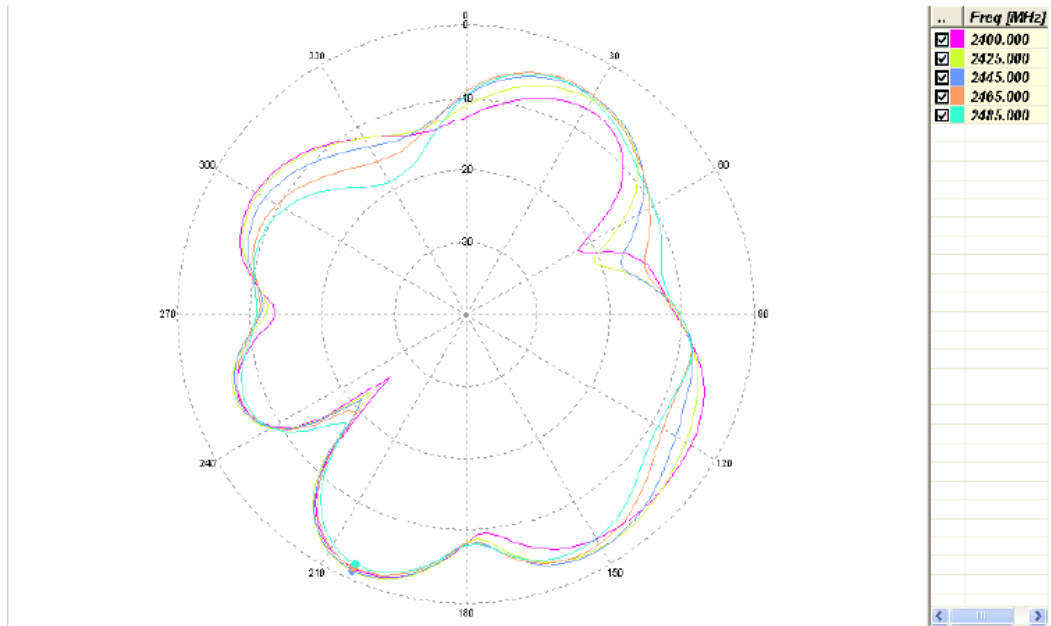
#### 4.5 Radiation Pattern

Azimuth Plane	Elevation1 Plane	Elevation2 Plane
Theta	Vertical field of measured plane	
Phi	Horizontal field of measured plane	





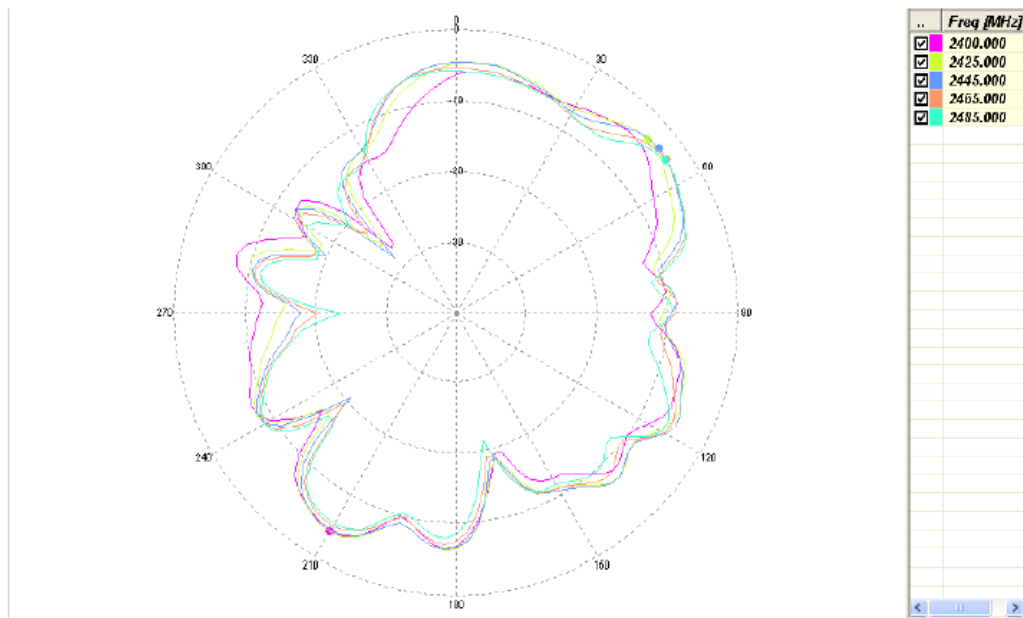
### Azimuth Phi



H-Plan [Vertical]

Frequency[MHz]	PeakValue	Theta[deg]	Phi[deg]	MinValue	Theta[deg]	Phi[deg]	3D Avg[dBi]	Gain[dBi]	Efficiency[%]
2400.000	-1.54	90	204	-25.29	90	231		-7.09	19.63
2425.000	-1.13	90	204	-22.99	90	231		-6.58	22.08
2445.000	-1.23	90	204	-21.28	90	231		-6.70	21.51
2465.000	-1.70	90	204	-19.64	90	228		-7.19	19.21
2485.000	-2.15	90	204	-18.72	90	333		-7.64	17.32

### Elevation1 Theta

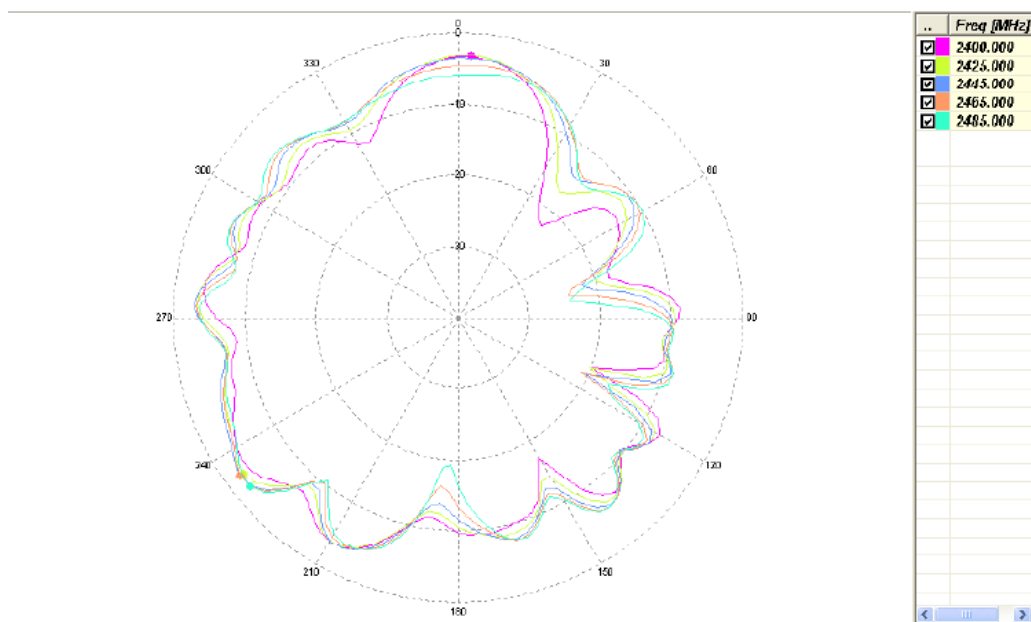


E1-Plan [Vertical]

Frequency[MHz]	PeakValue	Theta[deg]	Phi[deg]	MinValue	Theta[deg]	Phi[deg]	3D Avg[dBi]	Gain[dBi]	Efficiency[%]
2400.000	-4.06	210	0	-26.96	315	0		-8.59	13.95
2425.000	-3.36	49	0	-25.71	312	0		-7.84	15.54
2445.000	-2.99	51	0	-28.19	312	0		-7.74	16.95
2465.000	-3.09	54	0	-22.95	312	0		-8.27	14.99
2485.000	-3.28	54	0	-23.55	270	0		-8.68	13.65



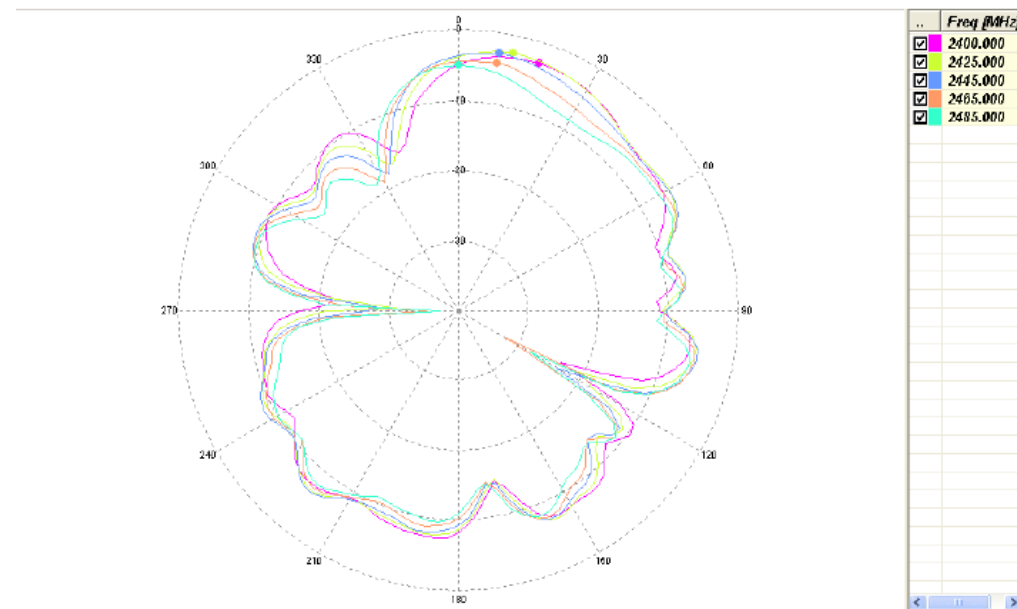
### Elevation1 Phi



E1-Plan [Horizontal]

Frequency [MHz]	Peak Value	Theta [deg]	Phi [deg]	Min Value	Theta [deg]	Phi [deg]	30 Avg [dB]	Gain [dB]	Efficiency [%]
2400.000	-3.05	3	0	-22.54	42	0		-7.80	16.72
2425.000	-2.80	234	0	-20.30	111	0		-7.25	18.93
2445.000	-2.17	234	0	-22.04	76	0		-6.84	20.32
2465.000	-2.23	234	0	-24.11	78	0		-7.12	19.52
2485.000	-2.31	231	0	-24.14	81	0		-7.38	18.37

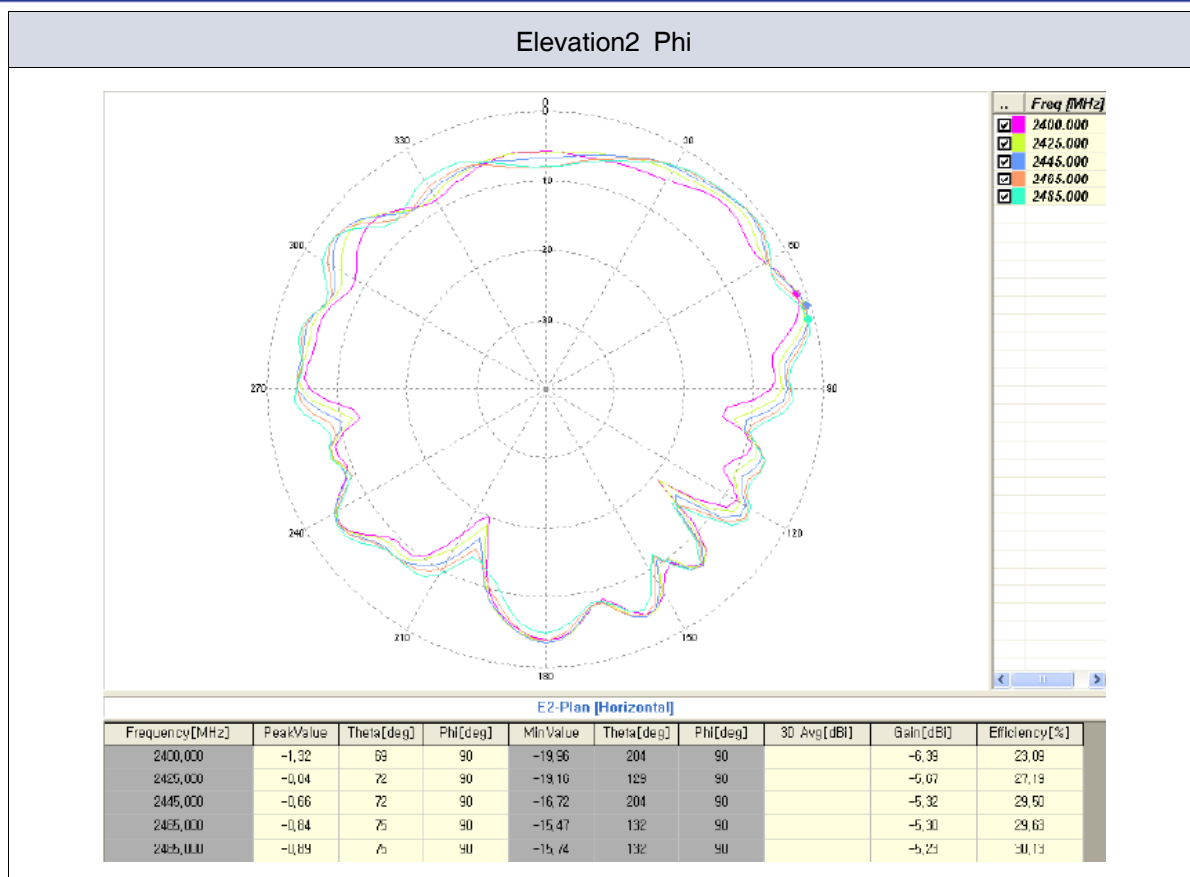
### Elevation2 Theta



E2-Plan [Vertical]

Frequency [MHz]	Peak Value	Theta [deg]	Phi [deg]	Min Value	Theta [deg]	Phi [deg]	30 Avg [dB]	Gain [dB]	Efficiency [%]
2400.000	-2.04	18	90	-23.64	117	90		-8.12	15.52
2425.000	-2.45	12	90	-31.57	273	90		-7.76	16.80
2445.000	-2.06	9	90	-28.77	273	90		-7.95	16.14
2465.000	-4.18	9	90	-35.32	270	90		-8.75	13.44
2485.000	-4.95	0	90	-37.25	270	90		-9.47	11.41

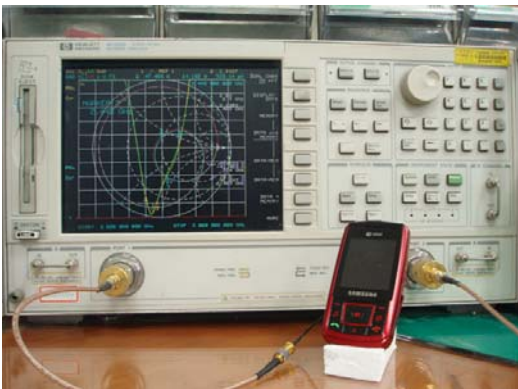
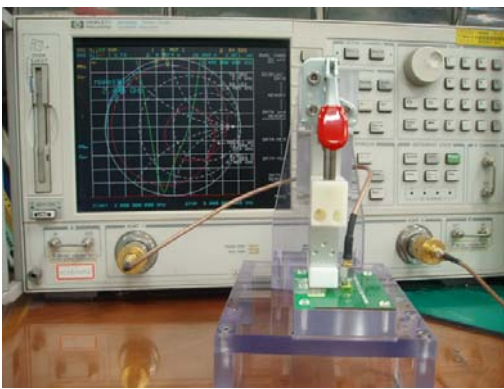




## 5. Measurement Process

### 5.1 SWR/Return loss

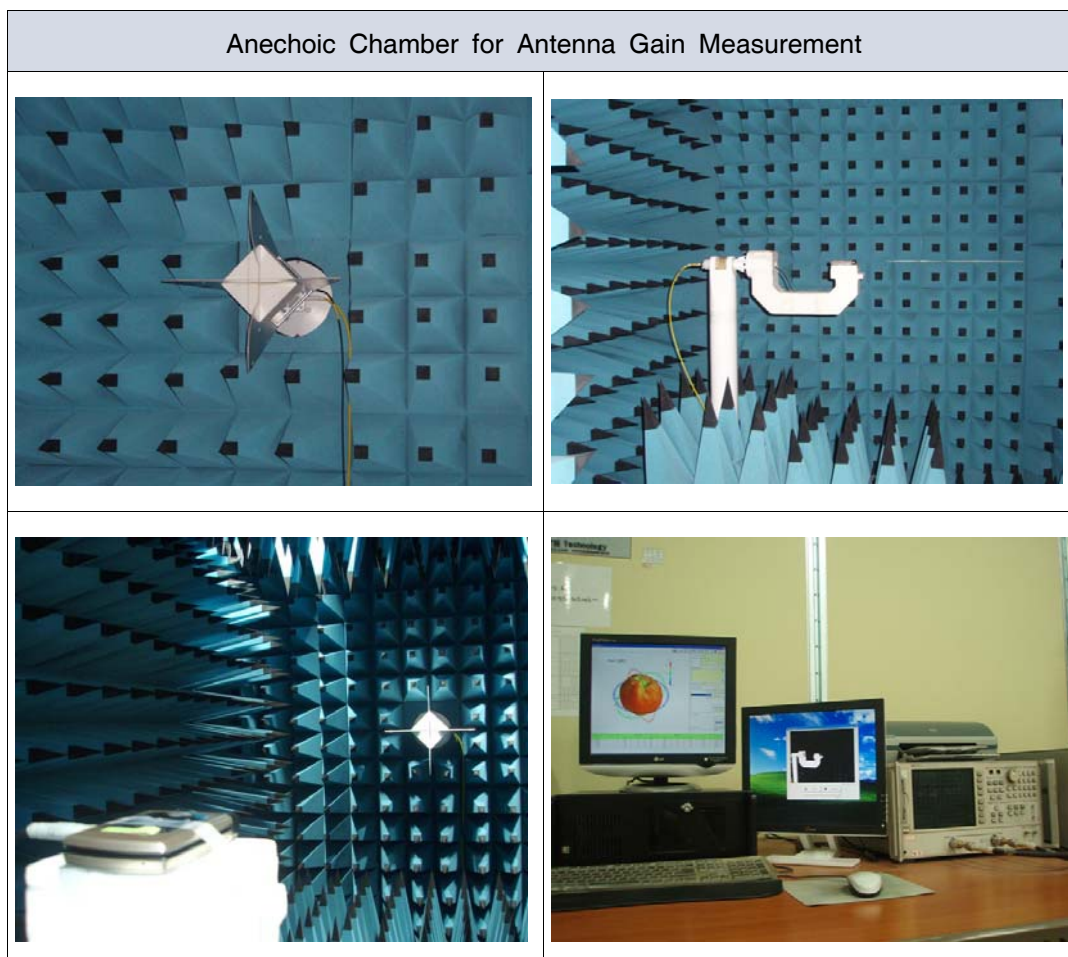
Use Network Analyzer when measuring SWR/Return loss and selecting standard SPL,  
Use automatic inspection equipment when selecting superior and inferior goods.

	Set Condition	Test Fixture Condition
Network Analyzer	Agilent HP8753D	Agilent HP8753D or Advantest R3765CH
Cable	RF cable(300mm)	RF cable(300mm)
Test condition		

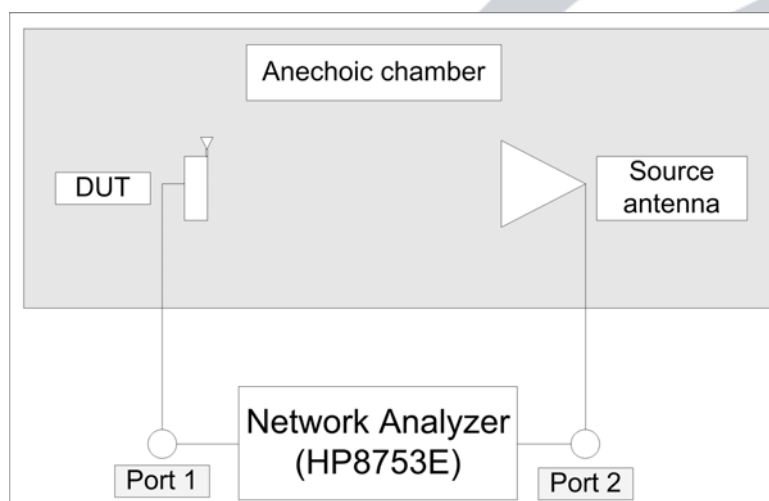


## 5.2 Gain

Antenna gain is measured in the Anechoic Chamber of this company, using set above of 4.1 list.



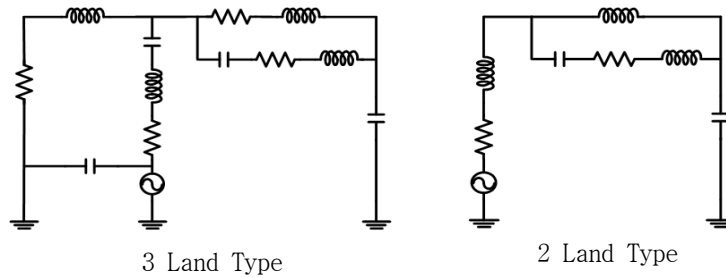
## 5.3 Gain test block diagram





## 6. Internal Block Diagram

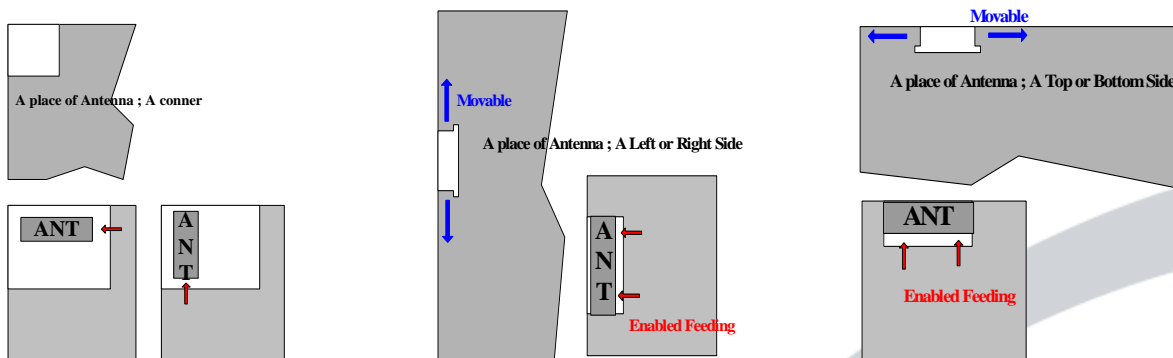
This product is made of the dielectric block and RF part materialized the characteristics by structural change of Ag pattern on the brick of dielectric block and conditioning value of the structural equivalent circuit.



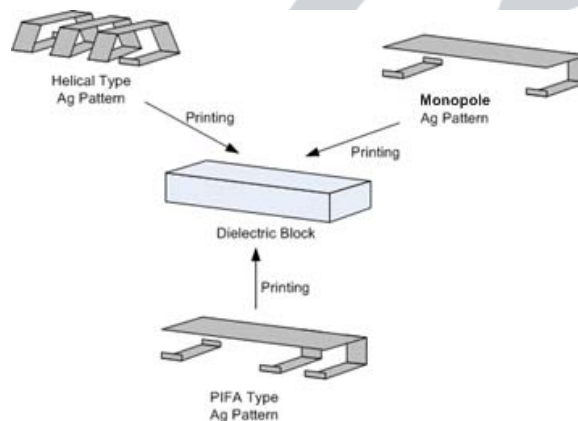
## 7. Basis Action / Application Note

This product is the internal dielectric chip antenna of radio communication, converts the electric signal advanced along by transmission line into free space wave.

This product will be mounted wherever you want and the design is revised by mount condition. But require attention to select the mount position, because this product is the radiation part and changed characteristics by boundary condition,



As the following, this product is easy to revise the various types for the boundary condition.





## 8. Measurement Jig SPEC

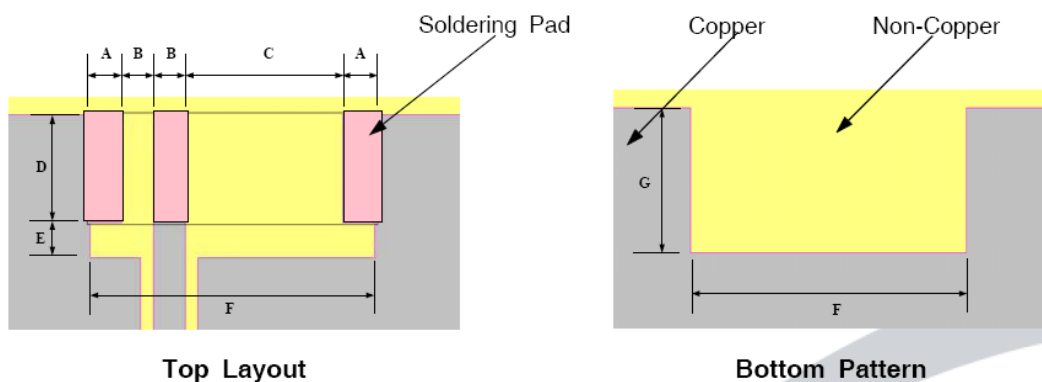
### 8.1 Test Fixture And GROUND Condition



※ Ev B'd and Test Fixture Jig is the same

( Contact way of Ev B'd is soldering, Test Fixture is copper contact way)

### 8.2 PCB Layout & Soldering Pad Dimension

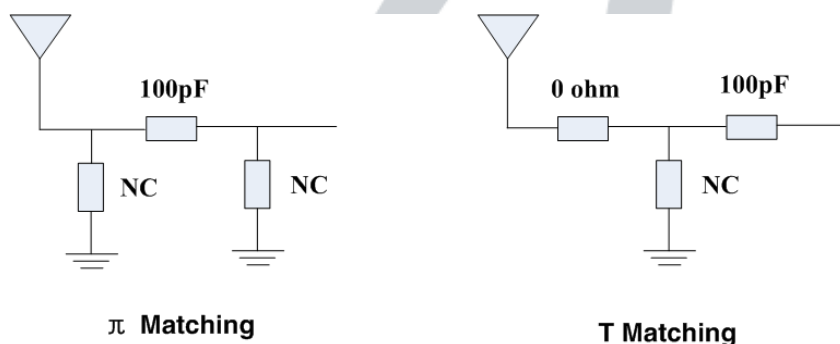


Parameter	A	B	C	D	E	F	G
Value[mm]	1.1	1.0	5.0	3.2	1.0	9.2	4.2

Unit ; mm

Unless specified tolerances are  $\pm 0.1$

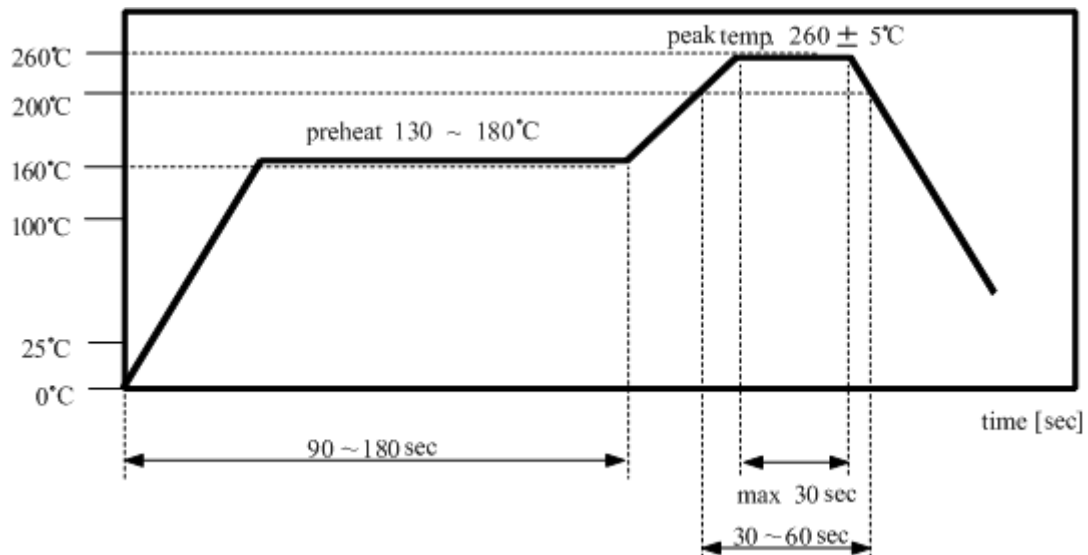
### 8.3 Matching Circuit And Reference Value





## 9. REFLOW PROFILE

### 9.1 Reflow Soldering



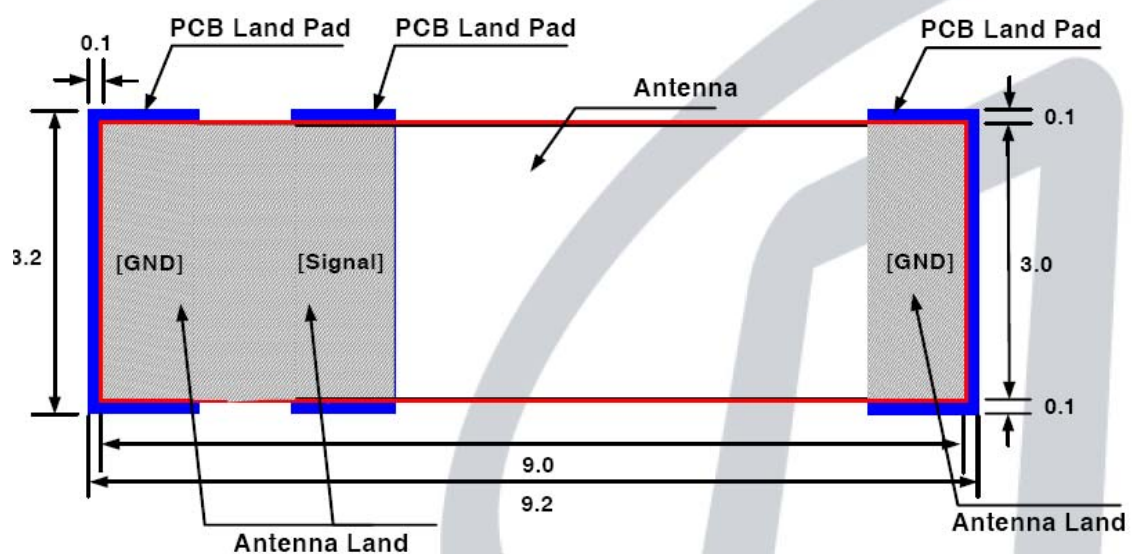
### 9.2 Manual Soldering

Pre-heating Temperature : 120°C , 60 ~ 300 sec.

Soldering Temperature : 340°C±5°C , 5sec max per each terminal


### 9.3 PCB Pattern Design

As the following, the PCB land pattern lays out 0.1mm outside land pattern of antenna more than indicated antenna land dimension





## 10. Primary Inspection List

Item	Electrical Characteristic[MHz] 		Size [mm]		
Standard	VSWR 3.0 MAX		W=3.0±0.1	L=9.0±0.1	T=1.2±0.1
	2400 MHz	2485 MHz			
1	1.71	1.66	3.03	9.02	1.21
2	1.64	1.73	3.02	9.01	1.22
3	1.64	1.72	3.02	9.02	1.22
4	1.67	1.71	3.01	9.01	1.21
5	1.65	1.73	3.02	8.99	1.24
6	1.59	1.78	3.04	9.00	1.23
7	1.77	1.59	3.01	9.03	1.22
8	1.57	1.77	3.01	9.00	1.23
9	1.57	1.80	3.04	9.02	1.23
10	1.63	1.73	3.03	9.02	1.24
11	1.65	1.78	3.02	9.01	1.21
12	1.62	1.71	3.02	9.00	1.22
13	1.58	1.78	3.04	8.99	1.21
14	1.62	1.77	3.01	9.01	1.23
15	1.70	1.64	3.01	9.01	1.24
16	1.58	1.72	3.02	9.00	1.23
17	1.58	1.74	3.01	9.01	1.22
18	1.62	1.75	3.04	9.00	1.22
19	1.65	1.71	3.03	9.02	1.21
20	1.58	1.79	3.02	9.01	1.21
Min	1.57	1.59	3.01	8.99	1.21
Max	1.77	1.60	3.04	9.03	1.24
X	1.63	1.73	3.02	9.01	1.22
σ	0.05	0.05	0.01	0.01	0.01
Cpk	8.53	7.86	2.28	2.79	2.38
Decision	ok	ok	ok	ok	ok



## 11. Reliability Condition

### 11.1 Environment Test

ITEM	TEST CONDITION	LIMIT
High Temperature Action	85℃±3℃, 1hr	After test, Must meet the characteristics spec of 4.4 list
High Temperature Resistance	+85℃±3℃, 120hr±2hr	
Low Temperature Action	-40℃±3℃, 1hr	
Low Temperature Resistance	-40℃±3℃, 120hr±2hr	
Humidity Action	+85±3℃, RH85%	
Humidity Resistance	+85±3℃, RH85%, 120hr±2hr	

### 11.2 Thermal shock test , Reflow test

ITEM	TEST CONDITION	LIMIT
Thermal shock	condition : -40℃±3℃/1min ↔ +85℃±3℃/1min Test Cycle : 32 cycle Temperature change time : within 5 min	After test, Must meet the characteristics spec of 4.4 list
Reflow	Pre Heating : 200±5℃, 30~60 sec Peak Heating : 260℃±5℃, 30sec Max	

### 11.3 Mechanical Test

ITEM	TEST CONDITION	LIMIT
Vibration	Freq : 10~500Hz , Acceleration : 10 ×9.8m/s <sup>2</sup> (G) Sweep time : 15 min , X.Y.Z each 5 times	After test, Must meet the characteristics spec of 4.4 list
Drop	18 times free fall Using the drop jig 152cm high Jig : 120g±20g Plastic Jig Bottom : Concrete or Iron	

### 11.4 MSL LEVEL Test

#### 1) JEDEC J-STD-020C Test

	Floor Life		Soak Requirements	
	Time	Conditions	Time	Conditions
1	Unlimited	= < 30℃/85%RH	168+5/-0	= < 85℃/85%RH

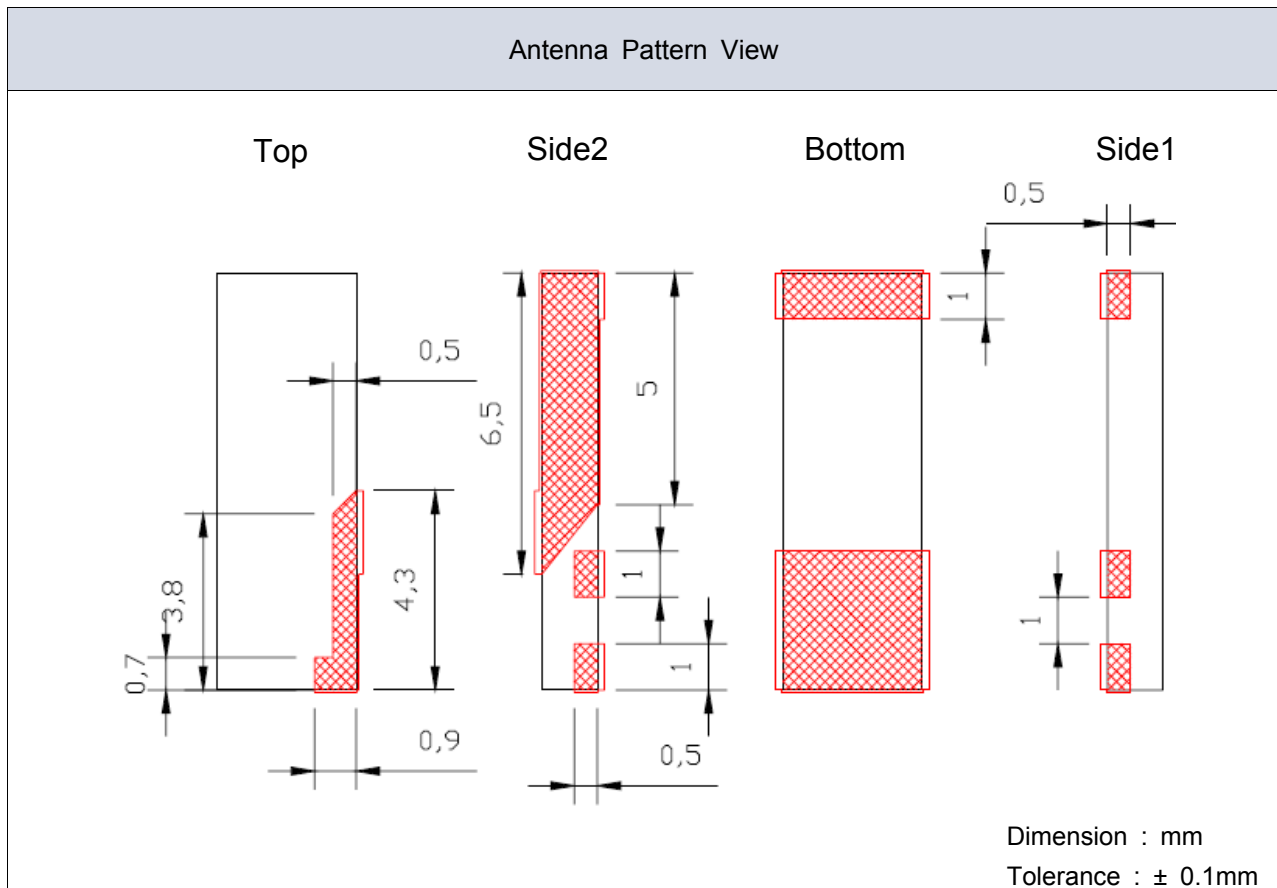
#### 2) Test Condition

ITEM	Conditon	LIMIT
Soak Requirements	After leaving +85±3℃, RH85% 168hr±2hr 2 times Reflow without aging	After test, Must meet the characteristics spec of 4.4 list

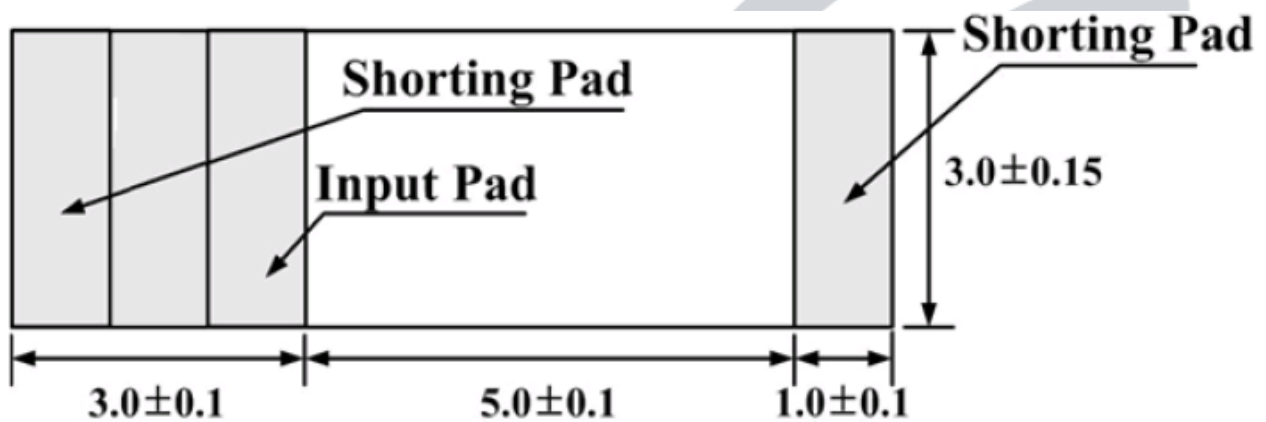


## 12. Mechanical Characteristics

### 12.1 Antenna Pattern Dimension



### 12.2 Pin name



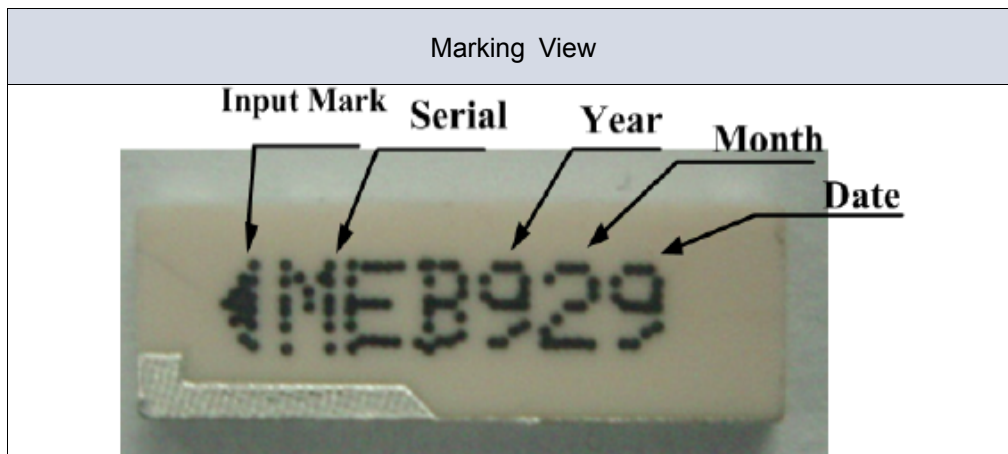


### 12.3 Lot number notation

<b>9</b>	<b>1</b>	<b>1</b>
①	②	③

- ① Year : 9 - 2009 ····  
 ② Month : 1 - January, 2 - February ··· 9 - September, A - October, B - November ···  
 ③ Date : 1 - 1st , 2 - 2nd ···· A - 10th, B - 11th ····

### 12.4 Marking



◀	<b>M</b>	<b>E</b>	<b>B</b>	<b>9</b>	<b>2</b>	<b>9</b>
①	②	③	④	⑤		

- ① Input Signal  
 ② Serial  
 ③ Year : 1 - 2001, 2 - 2002, ···· 9 - 2009 ····  
 ④ Month : 1 - January, 2 - February ··· 9 - September, A - October, B - November ···  
 ⑤ Date : 1 - 1st , 2 - 2nd ···· A - 10th, B - 11th ····

### 12.5 Marking type

Ink marking - Using Black Ink

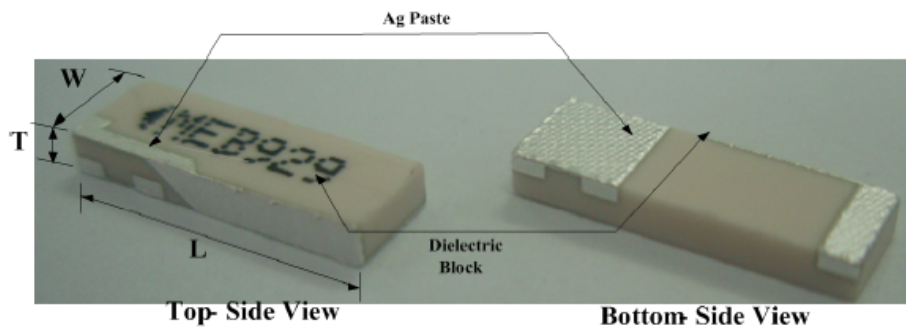


### 13. Structure and Material

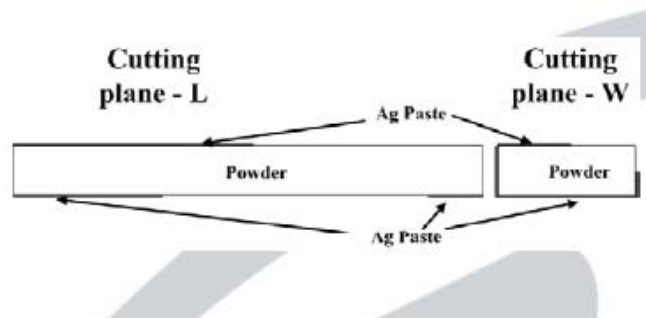
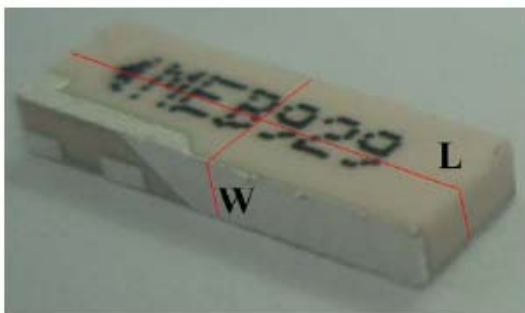
#### 13.1 materialization method

Chip antenna forms the pattern with Ag paste on the brick of dielectric block and materializes the characteristics

#### 13.2 Struture



#### 13.3 Internal cross section



#### 13.4 Material

ITEM	Material	Maker	Printing pattern SPEC
Dielectric Block	Powder	Fuji	
PATTERN	Ag Paste	Metech	Thickness : TYP 10 $\mu$ m
PAD	Ag paste	Metech	Thickness : Min 10 $\mu$ m (TYP 16~20 $\mu$ m)



## 14. Attention

### 14.1 Temperature Condition

	Range of Temperature	Unit
Application temperature	-40 ~ +85	℃
Keeping temperature	-40 ~ +85	℃

### 14.2 Temperature Test Condition

	Condition	Range of Temperature
Application temperature	Low	24hr normal action at -75℃
	High	24hr normal action at +150℃
Keeping temperature	Low	normal action when left for 1000hr at -75℃
	High	normal action when left for 1000hr at +85℃

\* Because of the keeping temperature problem, no admission when left over +85℃

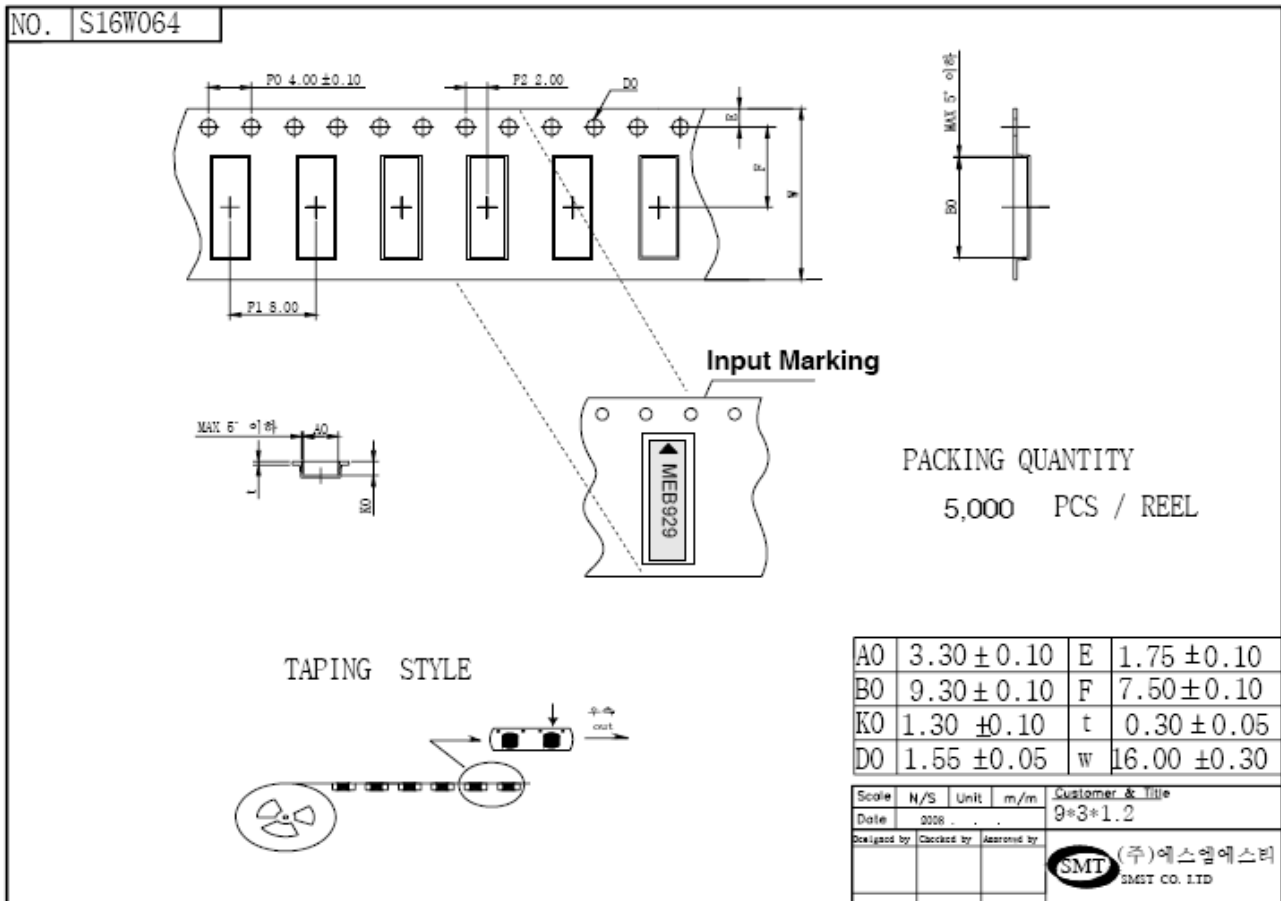




## 15. Packing

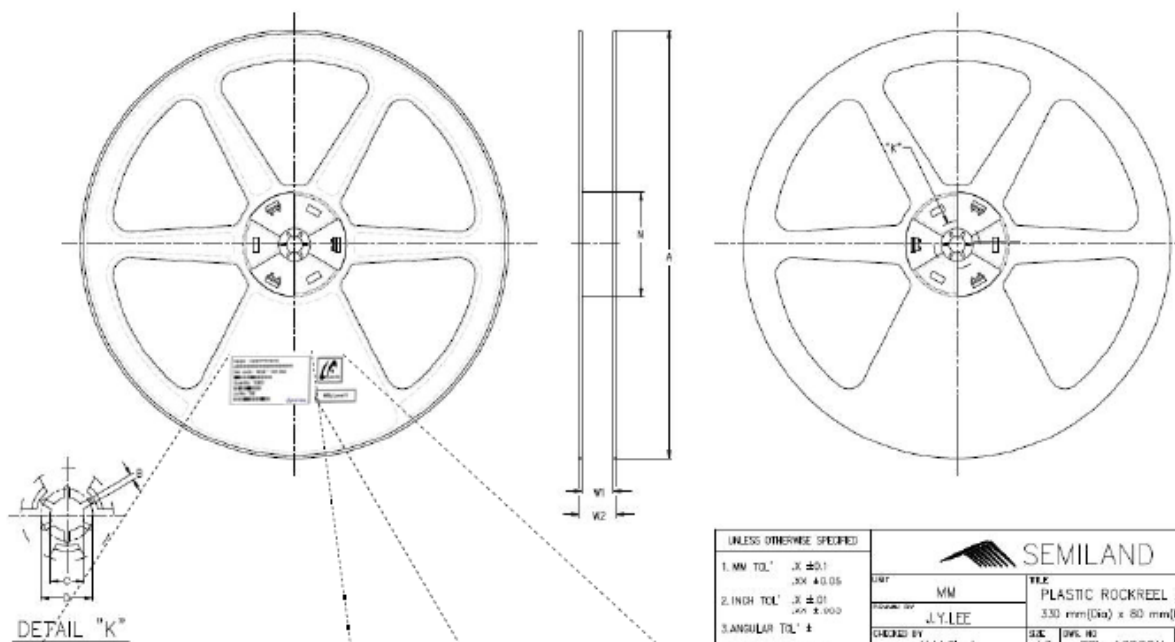
### 15.1 Carrier/Reel



ITEM	Material	Surface Resistance	electrostatic emission	Packing method
Carrier tape	A-PET	Typical $10^8\Omega$	10V MAX	Heat press
Cover tape	PET	Typical $10^8\Omega$	30V MAX	
Reel	PS	Typical $10^8\Omega$	30V MAX	-








Size	12mm	16mm	24mm	32mm	44mm	56mm
A	330 <sup>+28</sup> <sub>-28</sub>	330 <sup>+28</sup> <sub>-28</sub>	330 <sup>+28</sup> <sub>-28</sub>	330 <sup>+28</sup> <sub>-28</sub>	330 <sup>+28</sup> <sub>-28</sub>	330 <sup>+28</sup> <sub>-28</sub>
B	2.0 <sup>+0.5</sup> <sub>-0.5</sub>	2.0 <sup>+0.5</sup> <sub>-0.5</sub>	2.0 <sup>+0.5</sup> <sub>-0.5</sub>	2.0 <sup>+0.5</sup> <sub>-0.5</sub>	2.0 <sup>+0.5</sup> <sub>-0.5</sub>	2.0 <sup>+0.5</sup> <sub>-0.5</sub>
C	13.0 <sup>+2.5</sup> <sub>-2.5</sub>	13.0 <sup>+2.5</sup> <sub>-2.5</sub>	13.0 <sup>+2.5</sup> <sub>-2.5</sub>	13.0 <sup>+2.5</sup> <sub>-2.5</sub>	13.0 <sup>+2.5</sup> <sub>-2.5</sub>	13.0 <sup>+2.5</sup> <sub>-2.5</sub>
D	20.2min	20.2min	20.2min	20.2min	20.2min	20.2min
N	80 <sup>+30</sup> <sub>-30</sub>	80 <sup>+30</sup> <sub>-30</sub>	80 <sup>+30</sup> <sub>-30</sub>	80 <sup>+30</sup> <sub>-30</sub>	80 <sup>+30</sup> <sub>-30</sub>	80 <sup>+30</sup> <sub>-30</sub>
W1	12.4 <sup>+3.0</sup> <sub>-3.0</sub>	16.4 <sup>+3.0</sup> <sub>-3.0</sub>	24.4 <sup>+3.0</sup> <sub>-3.0</sub>	32.4 <sup>+3.0</sup> <sub>-3.0</sub>	44 <sup>+3.0</sup> <sub>-3.0</sub>	56.4 <sup>+3.0</sup> <sub>-3.0</sub>
W2	16.4 <sup>+3.0</sup> <sub>-3.0</sub>	20.4 <sup>+3.0</sup> <sub>-3.0</sub>	28.4 <sup>+3.0</sup> <sub>-3.0</sub>	36.4 <sup>+3.0</sup> <sub>-3.0</sub>	48.4 <sup>+3.0</sup> <sub>-3.0</sub>	60.4 <sup>+3.0</sup> <sub>-3.0</sub>



UNLESS OTHERWISE SPECIFIED		 <b>SEMILAND</b>	
1. MIN. TOL. : $\pm 0.1$		 <b>MM</b>	<b>PLASTIC ROCKREEL FOR</b> 330 mm(Dia) x 80 mm(Hub)
2. INCH TOL. : $\pm 0.01$			
3. ANGULAR TOL. : $\pm$		<b>J.Y.Lee</b>	<b>REV NO</b> A
4. UNLESS DIMS DOES NOT TO SCALE		<b>CHECKED BY</b> N.H.Choi	<b>DATE</b> 16 Oct 24 2006
		<b>APPROVED BY</b> Bando I-ae	<b>SCALE</b> 1:1

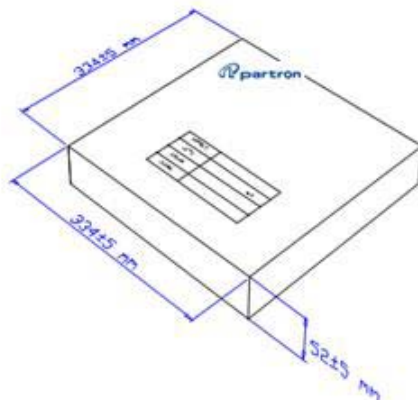
CODE NO :   
Model :   
Quantity :   
Lot No : 929



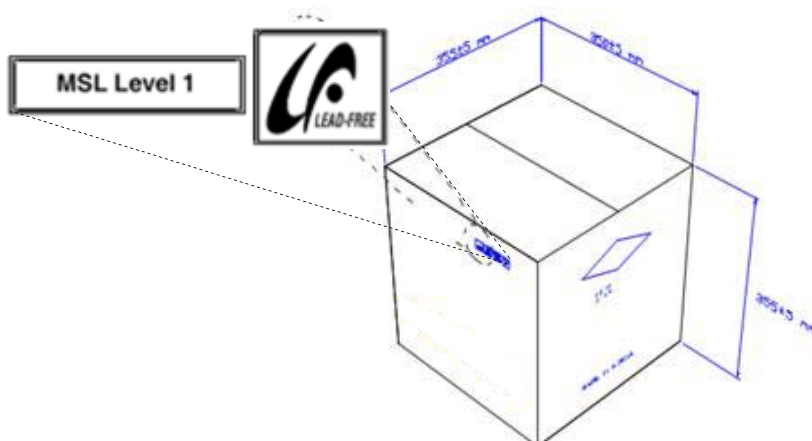
MSL Level 1



## 15.2 BOX



Material : SK/S/K-B  
Corrugated cardboard



## 15.3 Actual packing Picture



Reel



Internal Box





External Box










Reel / Internal Box label









External Box label



## 16. Process Control

Product		Issued/Revision		Process Control					Record	By designed	By checked	By approved		
CHIP ANTENNA		Issued	04.04.06						PRCP-C001					
Input Materials	FLOW CHART		Process name	Management of Factors					Management of quality					
	preparation	Main Process		Equipment Name	Checked	Condition	Cycle of management	Record	Checked Item	Margin	Method of Inspection	Cycle of management	Record	Action
Ceramic POWDER			Import Inspection						shrinking rate permittivity	refer to Guide Sheet	Micrometer Network	10ea/LOT	C/sheet	Return
POWDER lubricant			powder	Mixer					mixing	POWDER lubricant	Scale	PER MIXING	-	Exhaust
			Shaping	Press	pressure Mold Condition	refer to Guide Sheet	Per LOT 1/day	parameter C/SHEET	dimension weight density aspect	refer to Guide Sheet	Micrometer scale Calculated Visual	5/100EA 10ea/lot	LOT CARD	Exhaust
			Plasticity	Plasticity Hole	SETTER Outside Temperature PROFILE	refer to Guide Sheet	all 2/day 1/month	C/sheet						
			Block						wide length shape	refer to Guide Sheet	Micrometer Calipers Visual Inspection	20ea/LOT 20ea/LOT all	C/sheet	Exhaust
AG PASTE			SIDE1 PAD Printing	Printer screen	Squeeze velocity/presure SNAP	refer to Guide Sheet	1/day	-	PATTERN Dimension aspect	refer to Guide Sheet	Microscope	10ea/3Jig	c/sheet	Rework
			Dry	Dryer Dry Jig	Temperature Belt speed	refer to Guide Sheet	1/week	Parameter	Dry Condition Printed condition breakage	refer to Guide Sheet	Visual Inspection	all	Lot card	Rework



Product			Issued/Revision		Process Control					Record	By designed	By checked	By approved	
CHIP ANTENNA			Issued	04.04.06						PRCP-C001				
			Revised	05.04.03										
Input Materials	FLOW CHART		Process name	Management of Factors					Management of quality					
	preparation	Main Process		Equipment Name	Checked	Condition	Cycle of management	Record	Checked Item	Margin	Method of Inspection	Cycle of management	Record	Action
AG PASTE			SIDE 2 PAD Printing	Printer screen	Squeeze velocity/presure SNAP	refer to Guide Sheet	1/day	-	PATTERN Dimension aspect	refer to Guide Sheet	Microscope	10ea/3Jig	c/sheet	Rework
			Dry	Dryer Dry Jig	Temperature Belt speed	refer to Guide Sheet	1/week	Parameter	Dry Condition Printed condition breakage	refer to Guide Sheet	Visual Inspection	all	Lot card	Rework
			Baking	Baking Hole mesh net	Temperature Belt speed	refer to Guide Sheet	1/week	Parameter C/Sheet	Breakage Pollution	refer to Guide Sheet	Visual Inspection	all	Lot card	Exhaust Rework
AG PASTE			TOP printing	Printer screen	Squeeze velocity/presure SNAP	refer to Guide Sheet	1/day	-	PATTERN dimension	refer to Guide Sheet	measure	10ea/3Jig	c/sheet	Rework
			Dry	Dryer Dry Jig	Temperature Belt speed	refer to Guide Sheet	1/week	Parameter	Dry Condition Printed condition breakage	refer to Guide Sheet	Visual Inspection	all	Lot card	Rework
AG PASTE			BOTTOM PAD Printing CTQ	printer screen	Squeeze velocity/presure SNAP	refer to Guide Sheet	1/day	-	PATTERN dimension aspect	refer to Guide Sheet	measure Microscope	10ea/3Jig	c/sheet	Rework




Product			Issued/Revision		Process Control					Record	By designed	By checked	By approved	
CHIP ANTENNA			Issued	04.04.06						PRCP-C001				
Input Materials	FLOW CHART		Process name	Management of Factors					Management of quality					
	preparation	Main Process		Equipment Name	Checked	Condition	Cycle of management	Record	Checked Item	Margin	Method of Inspection	Cycle of management	Record	Action
	○		Dry	Dryer Dry Jig	Temperature Belt speed	refer to Guide Sheet	1/week	Parameter	Dry Condition Printed condition breakage	refer to Guide Sheet	Visual Inspection	all	Lot card	Rework
		○	Baking	Baking Hole mesh net	Temperature Belt speed	refer to Guide Sheet	1/week	Parameter C/Sheet	Breakage Pollution	refer to Guide Sheet	Visual Inspection	all	Lot card	Exhaust Rework
		◇	aspect inspection						aspect	Reference SPL refer to Guide Sheet	Visual Inspection microscope	all	Lot card production diary	Exhaust repair
		○	MARKING	Marking Machine					marking	Reference SPL	Visual Inspection	all	Lot card production diary	Rework Exhaust
		◇	Electrical Characteristic	NETWORK Inspection Jig	proofreading Condition	refer to Guide Sheet	1/2hour	C/sheet	Electrical Characteristic	refer to Guide Sheet	Network	all	Lot card production diary	Exhaust repair
		◇	aspect inspection						aspect dimension	Reference SPL refer to Guide Sheet	Visual Inspection microscope	all	Lot card production diary	Exhaust repair
Carrier cover reel		○	Taping						Quantity Direction aspect	refer to Guide Sheet	Manual	all	Lot card production diary	Rework
		◇	shipper inspection	NETWORK Inspection Jig	proofreading Condition	refer to Guide Sheet	1/person	C/sheet	Electrical Characteristic aspect packing	refer to Guide Sheet	Network microscope Visual Inspection	refer to Guide Sheet	Result Paper	return Exhaust
packing box label		○	packing	bar code printer					packing P/N Quantity	refer to Guide Sheet	Visual Inspection	all	-	Rework
		◇	packing inspection						packing P/N Quantity	refer to Guide Sheet	Visual Inspection	all	-	return



### 17.1 Ceramic Powder

Parts Name	White Powder(MMS-08)
Tester Organization	SGS Testing KOREA co. Ltd.
Measurement Tester	Please see the 'method' in the test report
Measurement Data	Please see the report under the table

<b>SGS</b>			
<b>Test Report</b>	No. : CE200925104    Date : 2009/02/05    Page : 1 of 4		
FUJII TITANIUM INDUSTRY CO., LTD. 1-3-1, SENSEI-CHO, HIRATA-SHI, KANAGAWA-PREF., JAPAN			
The following sample(s) was/were submitted and identified by/below the client as :			
Sample Description	MIXTURE OF MAGNESIUM SILICATE, STRONTIUM ZIRCONATE, BARIUM TITANATE		
Style/item No.	MMIS-08(B)		
Sample Receiving Date	2009/02/19		
Testing Period	2009/02/19 TO 2009/02/05		
Test Requested	In accordance with the RoHS Directive 2002/95/EC, and its amendment directives.		
Test Method	With reference to IEC 62321-1: 2008 Processes for the Determination of Levels of Regulated Substances in Electrotechnical Products.		
(1) Determination of Cadmium by ICP-AES. (2) Determination of Lead by ICP-AES. (3) Determination of Mercury by ICP-AES. (4) Determination of Hexavalent Chromium by UV/VIS Spectrometry.			
Test Result(s)	Please refer to next page(s).		
 Noriko Chino / Inspector Signed for and on behalf of SGS TWAIN LTD. Chemical Laboratory - Taipei			
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[illegible]

SGS

# Test Report

No.: CE/2009/2194 Date : 2009/02/06

Page : 3 of 4

FUJAI TITANIUM INDUSTRY CO., LTD.  
1-3-1, SENDOH-CHO, HIRAKATA-SITY, KANAGAWA-PREF, JAPAN

- 1) These samples were dissolved totally by pre-conditioning method according to below flow chart.  
(ICP-AES test method excluded)
- 2) Name of the person who made measurement: Chingmei Yang
- 3) Name of the person in charge of measurement: Troy Chang

```
graph TD; A[Cutting / Preparation] --> B[Sample Measurement]; B --> C[Pb-, Cu]; B --> D[Hg]; B --> E[Cr+]; C --> F["Acid digestion by sulfate and depended on different sample material (as below table)"]; D --> G["Microwave digestion with HNO3/HCl/HF"]; E --> H["Add appropriate amount of digestion reagent"]; F --> I[Filtration]; G --> I; H --> I; I --> J[Solution]; I --> K[Residue]; J --> L[ICP-AES]; K --> M["1) Alkali Fusion  
2) HCl to dissolve"]; M --> N[Heat to appropriate temperature to extract]; N --> O[Cool, filter digests through filter]; O --> P[Add diphenyl-carbazide for color development]; P --> Q[measure the absorbance at 540 nm by UV-VIS]
```

Sample Material	Digestion Acid
Steel, copper, aluminum, solder	Aqua regia, HNO <sub>3</sub> , HCl, HF, H <sub>2</sub> O <sub>2</sub>
Glass	HNO <sub>3</sub> /HF
Ceramic	Aqua regia
Gold, platinum, palladium, ceramic	HNO <sub>3</sub>
Silver	HNO <sub>3</sub>
Plastic	H <sub>2</sub> SO <sub>4</sub> /H <sub>2</sub> O <sub>2</sub> , HNO <sub>3</sub> , HCl
Others	Any acid to total digestion

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[illegible]



17.2 Ag Paste

Parts Name	Silver Paste
Tester Organization	SGS Testing KOREA co. Ltd.
Measurement Tester	Please see the 'method' in the test report
Measurement Data	Please see the report under the table

**SGS**

Test Report No. F06091LP-CTBAYAA08-27371 Issued Date: October 10, 2009 Page 1 of 2

To: METECH KOREA CO., LTD.  
8-501 Gyeongang Pangeon Office 17-2 Jeongja-dong  
Bundang-gu  
Gyeonggi-do  
Korea

The following merchandise was submitted and identified by the client as:

Product Name : Silver Paste  
SGS File No. : AYAA08-27371  
Received Date : October 06, 2009  
Test Performing Date : October 07, 2009  
Test Performed : SGS Testing Korea tested the sample(s) selected by applicant with following results.  
Test Results : For further details, please refer to following page(s).

SGS Testing Korea Co. Ltd.  
Pilsu Kim  
Manager Jeong  
Bilyu Ch / Testing Person

Jeff Jang / Chemical Lab Mgr

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**SGS**


Test Report No. F06091LP-CTBAYAA08-27371 Issued Date: October 10, 2009 Page 2 of 2

Sample No. : AYAA08-27371.001  
Sample Description : Silver Paste  
Item No./Part No. : PCC11837HV

**Heavy Metals**

Test Item	Unit	Test Method	MDL	Results
Cadmium (Cd)	mg/kg	US EPA 2052/1995, US EPA 8210B/1995, ICP	0.5	N.D.
Lead (Pb)	mg/kg	US EPA 2052/1995, US EPA 8210B/1995, ICP	5	N.D.
Mercury (Hg)	mg/kg	US EPA 2052/1995, US EPA 8210B/1995, ICP	2	N.D.
Hexavalent Chromium (Cr VI)	mg/kg	US EPA 2056A/1995, US EPA 7156A/1992, UV	1	N.D.

Picture of Sample as Received:



\*\*\* End \*\*\*

NOTE:  
(1) N.D. = Not detected (<MDL)  
(2) mg/kg = ppm  
(3) MDL = Method Detection Limit  
(4) - = No regulation  
(5) + = Qualitative analysis (No Unit)  
(6) Negative = Undetectable / Positive = Detectable

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### 17.3 Marking Ink(Black Ink)

Parts Name	Black Ink
Tester Organization	Intertek Testing Center
Measurement Tester	Please see the 'method' in the test report
Measurement Data	Please see the report under the table

**Intertek**

**TEST REPORT**

Report No. RT08R-10381-003 Page: 1 of 3  
Date: Oct. 07, 2008



Applicant: Imaje Korea Co., Ltd.  
Address: R# 1301, Daeyang TechnoTown 7<sup>th</sup>, 489-11, Gaeun-dong, Gumi-si, Gyeongju, Seoul, Korea

Sample Description: The following summarized sample(s) said to be:-  
Name/Type of Product: 5135E black ink  
Sample ID No.: RT08R-10381-003  
Manufacturer/Vender: Imaje Korea Co., Ltd.

Sample received: Sep. 30, 2008  
Testing Date: Sep. 30, 2008 ~ Oct. 07, 2008  
Testing Laboratory: Intertek Testing Center  
Testing Environment: Temperature: ( 22 ~ 26 ) °C Relative Humidity: ( 55 ~ 65 ) %

Test Method(s): Please see the following page(s).  
Test Result(s): Please see the following page(s).

\* Note 1: The test results presented in this report relate only to the subject tested.  
\* Note 2: This report shall not be reproduced except in full without the written approval of the testing laboratory.

Approved by:  Jade Jeng / Lab. Technical Manager  
Authorized by:  Bo Park / Lab. General Manager

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**Intertek Testing Center**

Seoul Office: Tel: 02-209-1250 Fax: 02-209-1259 Gumi Office: Tel: 054-462-7647 Fax: 054-462-7657 Web Site: [www.intertek.co.kr](http://www.intertek.co.kr)  
Seoul Lab: #100, 7th, Ase Techno Tower, 197-2, Guro-dong, Guro-gu, Seoul 152-761 Korea Tel: 02-209-1260 Fax: 02-209-1258  
Ulsan Lab: #340-2, Yongsan-Ri, Cheongpang-Myeon, Ulsan-Gu, Ulsan 689-865 Korea Tel: 052-257-4754 Fax: 052-276-4792

**Intertek**

**TEST REPORT**

Report No. RT08R-10381-003 Page: 2 of 3  
Sample ID No.: RT08R-10381-003  
Sample Description: 5135E black ink

Test Items	Unit	Test Method	MDL	Result
Cadmium (Cd)	ppm	With reference to US EPA 3052, by acid digestion and determined by ICP-OES.	0.5	N.D.
Lead (Pb)	ppm	With reference to US EPA 3052, by acid digestion and determined by ICP-OES.	5	N.D.
Mercury (Hg)	ppm	With reference to US EPA 3052, by acid digestion and determined by ICP-OES.	2	N.D.
Hexavalent Chromium (Cr <sup>6+</sup> )	ppm	With reference to US EPA 3061a and determined by UV-VIS Spectrophotometer.	1	N.D.
<b>Polybrominated Biphenyl (PBBs)</b>				
Mono-bromobiphenyl	ppm	With reference to US EPA 3543C, by solvent extraction and determined by GC/MS.	5	N.D.
Dibromobiphenyl	ppm		5	N.D.
Tribromobiphenyl	ppm		5	N.D.
Tetra-bromobiphenyl	ppm		5	N.D.
Penta-bromobiphenyl	ppm		5	N.D.
Hexa-bromobiphenyl	ppm		5	N.D.
Hepta-bromobiphenyl	ppm		5	N.D.
Octa-bromobiphenyl	ppm		5	N.D.
<b>Polybrominated Diphenyl Ether (PBDEs)</b>				
Mono-bromodiphenyl ether	ppm	With reference to US EPA 3543C, by solvent extraction and determined by GC/MS.	5	N.D.
Dibromodiphenyl ether	ppm		5	N.D.
Tribromodiphenyl ether	ppm		5	N.D.
Tetra-bromodiphenyl ether	ppm		5	N.D.
Penta-bromodiphenyl ether	ppm		5	N.D.
Hexa-bromodiphenyl ether	ppm		5	N.D.
Hepta-bromodiphenyl ether	ppm		5	N.D.
Octa-bromodiphenyl ether	ppm		5	N.D.

Notes: ppm = parts per million  
N.D. = Not detected (<MDL)  
MDL = Method detection limit

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Ulsan Lab: #340-2, Yongsan-Ri, Cheongpang-Myeon, Ulsan-Gu, Ulsan 689-865 Korea Tel: 052-257-4754 Fax: 052-276-4792

**Intertek**

**TEST REPORT**


Report No. RT08R-10381-003 Page: 3 of 3  
Sample ID No.: RT08R-10381-003  
Sample Description: 5135E black ink

Test Items	Unit	Test Method	MDL	Result
Bromine (Br)	ppm	With reference to EPA 1450.2, by oxygen combustion with bomb and determined by IC.	30	N.D.
Chlorine (Cl)	ppm	With reference to EPA 1450.2, by oxygen combustion with bomb and determined by IC.	30	N.D.

Tested by: Nikkie Lee

Notes: ppm = parts per million  
N.D. = Not detected (<MDL)  
MDL = Method detection limit

\* View of sample as received:-



\*\*\*\*\* End of Report \*\*\*\*\*

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